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Application No. <u>09/362,200</u>	Prepared by <u>NPB</u>	Tracking Number <u>05886243</u>	
Examiner-GAU <u>ECKERT - 2815</u>	Date <u>2/11/04</u>	Week Date <u>1/5/04</u>	
	No. of queries <u>2</u>	<u>IFW</u>	

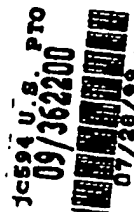
JACKET			
a. Serial No.	f. Foreign Priority	k. Print Claim(s)	p. PTO-1449
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

SPECIFICATION	MESSAGE
a. Page Missing	<p>(1) PTO-1449: other documents: Please either initial or line through citations. (copy provided for reference - please see attached).</p> <p>(2) Bottom page of drawing pages 13 and 21 (FIGS. 18 and 29) are cut-off. Please supply new page. (copy provided for reference - please see attached)</p> <p style="text-align: right;">Thumkya</p>
b. Text Continuity	
c. Holes through Data	
d. Other Missing Text	
e. Illegible Text	
f. Duplicate Text	
g. Brief Description	
h. Sequence Listing	
i. Appendix	
j. Amendments	
k. Other	
<p>CLAIMS</p> <p>a. Claim(s) Missing</p> <p>b. Improper Dependency</p> <p>c. Duplicate Numbers</p> <p>d. Incorrect Numbering</p> <p>e. Index Disagrees</p> <p>f. Punctuation</p> <p>g. Amendments</p> <p>h. Bracketing</p> <p>i. Missing Text</p> <p>j. Duplicate Text</p> <p>k. Other</p>	
	<p>RESPONSE The examiner initialized the PTO-1449 and provided corrected copies of figures 18 and 29.</p> <p style="text-align: right;">initials <u>mm</u></p> <p style="text-align: right;">EU</p> <p style="text-align: right;">initials</p>

FORM PTO-1449
INFORMATION DISCLOSURE
STATEMENT BY APPLICANT(S)

Sheet 1 of 2

Atty Docket No.: 2369/23
Serial No. :
Applicants : K. NAKAZATO et al.
Filed :
Group Art Unit:
Examiner :



U.S. PATENT DOCUMENTS

Examiner Initial	Patent Number	Patent Date	Name	Class/ Subclass	Filing Date
<u>EO</u>	3,878,549	04/15/75	YAMAZAKI et al.	357/23	09/11/73
<u>EO</u>	5,604,357	02/97	HORI	257/324	
<u>EO</u>	5,286,994	02/94	OZAWA et al.	257/324	
<u>EO</u>	5,319,229	06/94	SHIMOJI et al.	257/324	
<u>EO</u>	5,216,262	06/93	TSU	257/411	

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class/ Subclass	Translation Yes No
<u>EO</u>	2 111 866	06/09/72	France		ABS.
<u>EO</u>	0 842 173	03/08/95	EPO		N/A
<u>EO</u>	WO 94/15340	07/07/94	Great Britain		N/A

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner Initial	
<u>EO</u>	1. IEEE TRANSACTIONS ON ELECTRON DEVICES, Vol. 43, No. 9, Sept. 1996, pp. 1553-1558, Hanati et al.; <i>Fast and Long Retention-Time Nano-Crystal Memory</i>
<u>EO</u>	2. MICROELECTRONIC ENGINEERING, Vol. 32, No. 1/04, Sept. 1996, pp. 297-315, H. Ahmed et al.; <i>Single-Electron Devices</i>

EXAMINER

DATE CONSIDERED

Edmund Ditz

10/4/01

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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INFORMATION DISCLOSURE
STATEMENT BY APPLICANT(S)

Sheet 2 of 2

#C9/362,100

Atty Docket No. : 2369/23
Serial No. :
Applicants : K. NAKAZATO et al.
Filed :
Group Art Unit :
Examiner :

OTHER DOCUMENTS
(Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner
Initial

EO

3. PHYSICAL REVIEW, B: CONDENSED-MATTER, Vol. 50, No. 12, 15 Sept. 1994, pp. 8961-8964, Bar-Sadeh et al.: *Single-Electron Tunneling Effects in Granular Metal Films*

EO

4. IEEE TRANSACTIONS ON ELECTRON DEVICES, Vol. 41, No. 9, Sept. 1994, pp. 1628-1638, K. Yano et al.: *Room-Temperature Single-Electron Memory*

EO

5. 1996 IEEE INTERNATIONAL SOLID-STATE CIRCUITS CONFERENCE, pp. 266-268, K. Yano et al.: *Single-Electron-Memory Integrated Circuit for Giga-to-Tera Bit Storage*

EO

6. APPL. PHYS. LETT. 68 (10), 4 March 1996, pp. 1377-1379, Sandip Tiwan et al.: *A Silicon Nanocrystals-based Memory*

EO

7. IEEE ELECTRON DEVICE LETTERS, Vol. EDL 1, No. 9, September 1980, pp. 179-181, DiMaria et al.: *Electrically-Alterable Memory Using A Dual Electron Injector Structure*

EXAMINER

DATE CONSIDERED

Kobayashi

10/6/01

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Serial No. **09/362,200** (including cover)

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In accordance with your telephone message, attached please find Figures 13 and 29 as you requested.

If you have any further questions or comments, please feel free to contact me.

David J. Zibelli

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E.O. (2815)
3/30/04

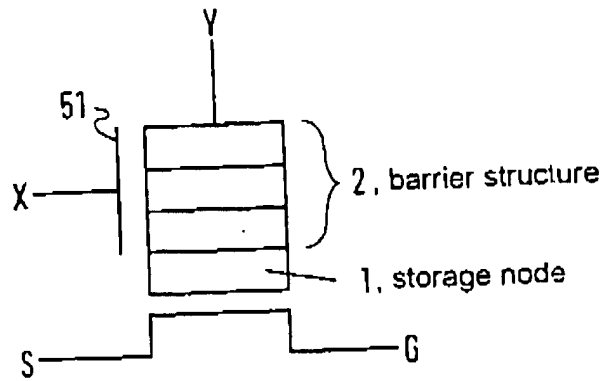


FIG. 17

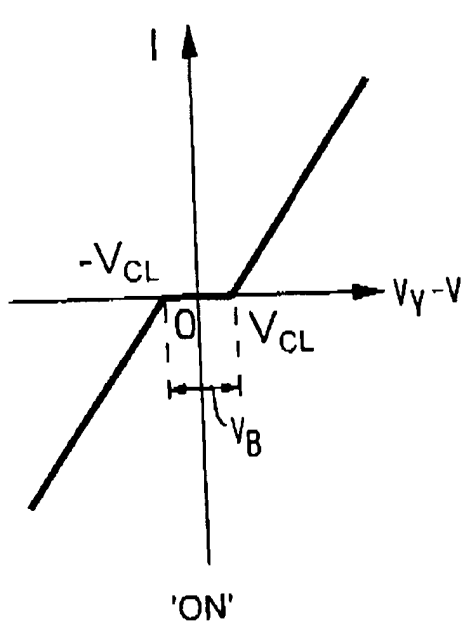


FIG. 18A

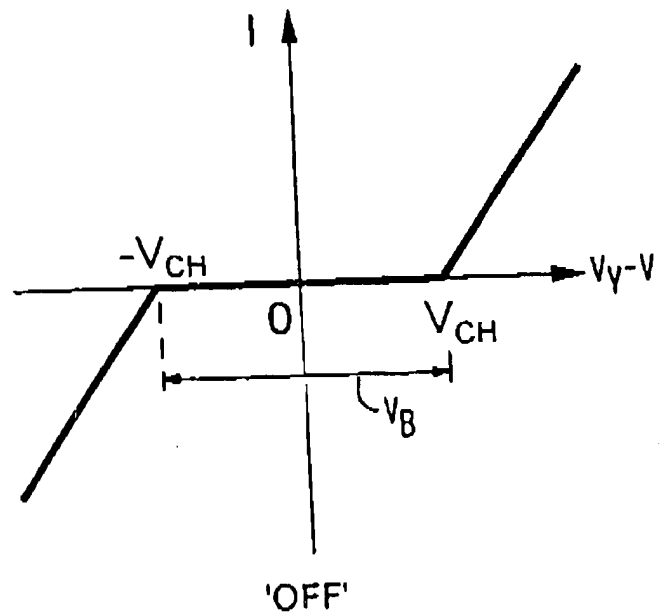


FIG. 18B

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F.O. (2015)
3/30/04

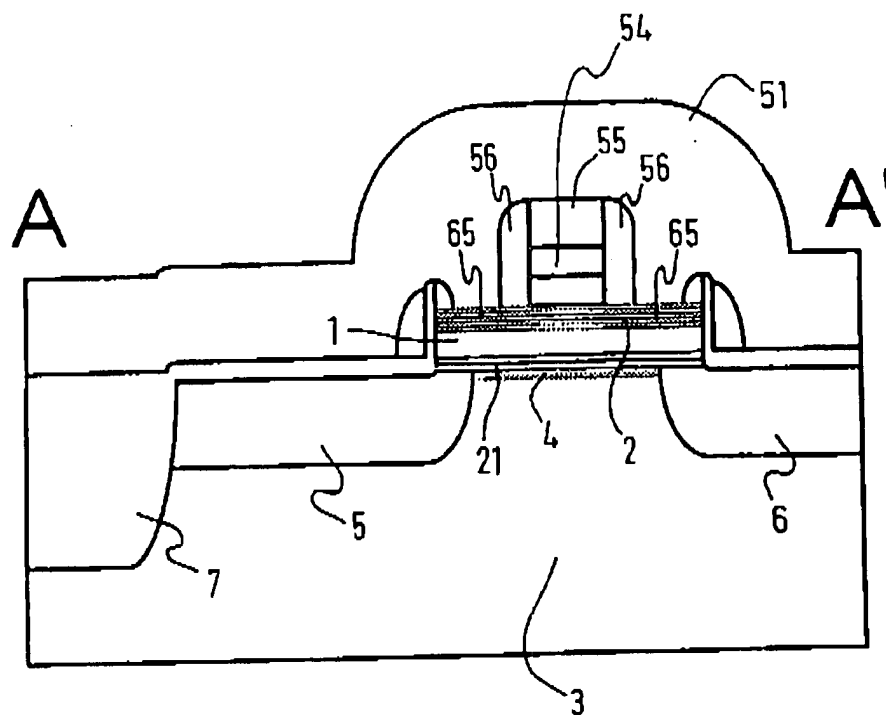


FIG. 28

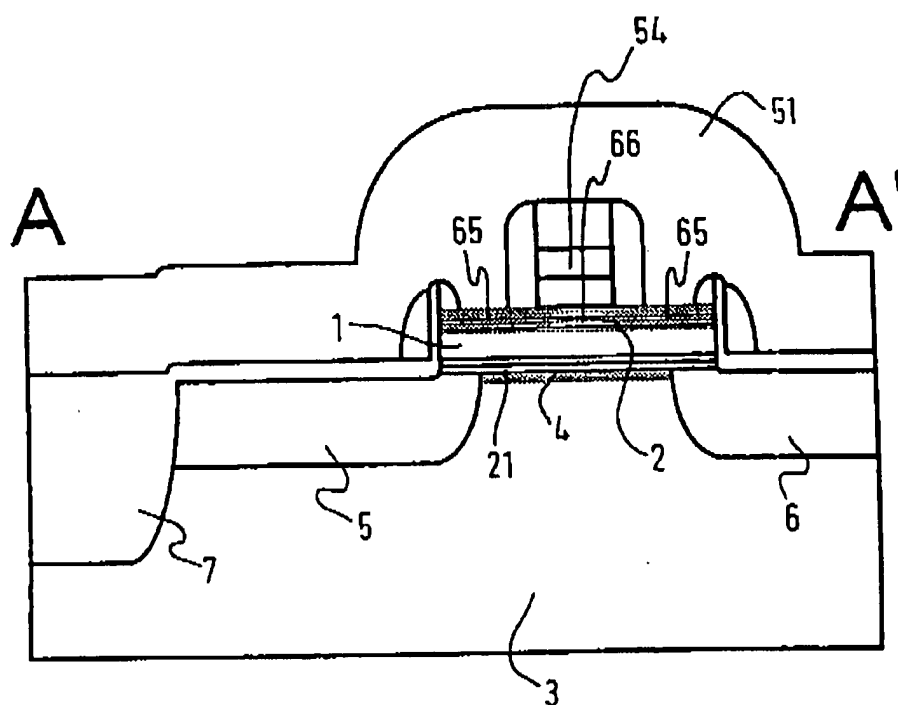


FIG. 29